

Lab #5: CMOS Logic Gates

Introduction

Digital circuitry forms the foundation of the modern technical, information-centric world. All digital circuits, from simple combinational logic circuits to sophisticated microprocessors, employ logic gates that perform the basic Boolean functions such as AND, OR, NAND, NOR, etc. All of the basic logic gates are implemented in the major logic families. The CMOS (complementary metal-oxide semiconductor) family is currently the most widely used because of its low power dissipation properties, its relatively low cost of fabrication, and its high density of gates in integrated circuit (IC) chips. In this lab exercise you will analyze the operation of a basic CMOS logic gate. Group assignments are listed at the end of this handout.

Theoretical Background

The fundamental logic gate in any logic family is the NOT gate, or inverter. The output of a NOT gate is simply the complement of the input. That is, a logical input of 0 yields a logical output of 1, and vice versa. The other types of combinational logic gates, the AND, OR, NAND, NOR, XOR, and XNOR gates, have two or more inputs. For two-input gates with inputs labeled A and B , the following truth table defines the output states for the indicated Boolean operations.

Inputs		Boolean Operation					
A	B	AND	NAND	OR	NOR	XOR	XNOR
0	0	0	1	0	1	0	1
0	1	0	1	1	0	1	0
1	0	0	1	1	0	1	0
1	1	1	0	1	0	0	1

In the CMOS logic family, these Boolean operations are implemented on IC chips that contain both p -channel (PMOS) and n -channel (NMOS) MOSFETs. For enhancement-mode NMOS devices in normal operation, the drain current i_{Dn} , the gate-to-source voltage v_{GSn} , the drain-to-source voltage v_{DSn} , the threshold voltage V_{tn} , and the transconductance parameter $k_n = \mu_n C_{ox} W/L$ are all positive quantities. For PMOS devices, the quantities i_{Dp} , v_{SGp} , v_{SDp} , and the parameter $k_p = \mu_p C_{ox} W/L$ are also positive, but the threshold voltage V_{tp} is negative. Positive drain current is defined as flowing out of the drain terminal in PMOS devices.

Typical i - v characteristics for NMOS and PMOS devices are shown in Figure 1. During normal operation, all NMOS devices in the equilibrium state, which is defined as the case when the input and output voltages have settled to either a logical 0 or 1 representation, have gate-to-source voltages of either 0 V or V_{DD} , and all PMOS devices have source-to-gate voltages of either 0 V or V_{DD} . This implies that the operating point of each device lies along either the upper curve in one of the plots in Figure 1 or along the horizontal axis, which corresponds to the cut-off region. Note that the v_{GSn} or $v_{SGp} = V_{DD}$ curves and the v_{GSn} or $v_{SGp} = 0$ “curve” (the horizontal axis) in each plot intersect at the origin.

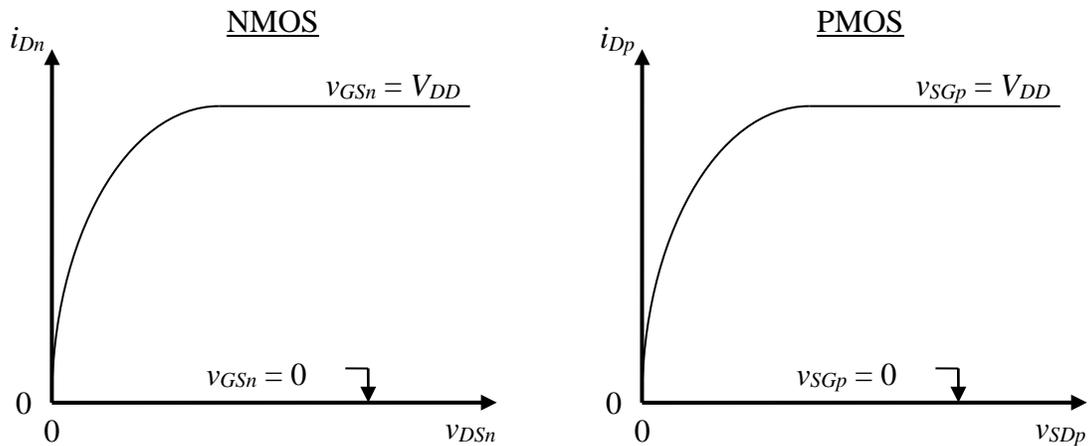


Figure 1. Graphical representations of the i - v characteristics for n -channel (left) and p -channel (right) MOSFETs for two different values of the gate-to-source or source-to-gate voltage. These represent the two possible steady states (i.e., not in a logic transition) of a MOSFET in a CMOS logic gate.

When in the equilibrium state, the transistors in a CMOS gate operate in either the cut-off region or the triode region because the drain current through all of the transistors is practically zero. Examination of Figure 1 shows that an NMOS device or a PMOS device can have zero drain current when it is in the triode region if v_{DSn} or $v_{SDp} = 0$. The region of operation is determined by the value of v_{GSn} for NMOS devices and by v_{SGp} for PMOS devices.

Experimental Procedure

You will be given a blank truth table and a circuit diagram for a CMOS logic gate that implements an unknown (to you) Boolean operation. The NMOS and PMOS symbols used in the diagram have the more complicated form that includes the substrate (body) terminal. The reason for this will be explained at the beginning of the lab session. Complete the following items:

- Using the NMOS and PMOS i - v characteristics in Figure 1 as a guide, complete the truth table for the circuit, and determine the Boolean operation (NOT, AND, OR, NAND, NOR, XOR, or XNOR) that the circuit implements. Also determine to the best of your ability the region of operation of each of the four MOSFETs for each input state (00, 01, 10, and 11). Add all of this information as well as your names to the MS-Word file corresponding to the gate type assigned to your group. Also indicate the logical gate type. The documents with the circuit diagrams and truth tables are available on the Laboratory page at the course web site.

You should discover that determining the region of operation for one of the MOSFETs will be more challenging than for the other three, particularly for one of the four input states. However, for that case you should be able to predict the overall output state of the logic gate regardless of the operating region of that particular MOSFET. To determine the region of operation, assume one of the two likely possibilities (cut-off or triode) and then look for contradictions.

- After you have completed the steps above and everyone in the lab group confirms that they have a good grasp of how the circuit operates, schedule a meeting with me to take place at a mutually available time before the end of the semester. Several time slots will be available during the last lab session (Tuesday, December 5). During the meeting, you will demonstrate your knowledge of the circuit following the guidelines given in the next section.
- Before the meeting, e-mail to me the completed MS-Word worksheet corresponding to the logic gate type assigned to your group. Name the file “LName1_LName2_LName3_Lab5_fa23.docx,” where LName1, etc. are the last names of your group members. Add a fourth name if necessary.

Post-Lab Meeting

Read this entire section before the post-lab meeting. The following guidelines apply:

- Meetings will be scheduled in the order that requests are received.
- The meeting must be completed before 6:00 pm on Tuesday, December 5. Meetings will not be rescheduled if the first one reveals a lack of preparation.
- All group members must be present.
- If the meeting is completed within a lab session, your group does not have to be in the lab room outside of the scheduled meeting time.
- Deadline extensions for confirmed illnesses or other extenuating circumstances will generally be approved. However, if the meeting cannot be rescheduled before classes end, then other arrangements will be made.

During the meeting, each lab group member must explain how the logical output state and the regions of operation of all four MOSFETs were determined for one of the logical input combinations listed below. The input states may be pre-assigned to the lab group members; that is, they do not have to be randomly selected during the meeting. To facilitate each explanation, a high-quality copy of the logic gate’s circuit diagram must be accessible during the meeting.

- $A = 0, B = 0$
- $A = 0, B = 1$
- $A = 1, B = 1$
- $A = 1, B = 0$ if the group has four members

Each person will have a time limit of **five minutes** to complete their explanation. Individual scores will be based on the accuracy and thoroughness of the response, the comprehension of the applicable concepts, and overall preparation for the meeting.

If the group has only three members, then there will be a general discussion regarding the $A = 1, B = 0$ input state (the fourth one listed above).

Extra Credit Opportunity

Your group may complete **one** of the following two options to add up to 10 points to each group member's overall score. Each member who wishes to receive extra points must be present at the demonstration. The demonstration must be completed within **five minutes**; no extensions will be granted for wiring or software issues. Presentation quality and circuit operation will carry equal weight. The number of points added will be determined as follows:

10 pts – proper operation with clearly labeled terminals and clearly indicated input states and output voltages

5 pts – presence of a major deficiency in one or two of these requirements

2 pts – presence of multiple deficiencies

- Option 1: Simulate the logic gate assigned to your group in *Multisim*. You must use *Multisim* voltage probes to monitor the gate's output voltage v_O and the node voltage between the two "stacked" MOSFETs (Q_3 and Q_4 in gate A and Q_1 and Q_2 in gate B). You must also use SPDT (single-pole, double-throw) switches at the input terminals to allow rapid, real-time changes in the input voltages from 0 V (logical 0) to V_{DD} (logical 1). Change the key designations of the switches to "A" and "B" to match the input labels. Use the generic MOS_N_4T and MOS_P_4T devices available in the "TRANSISTORS_VIRTUAL" family of the "Transistors" component group. You must provide appropriate connections between the substrate (body) terminal and either ground or V_{DD} for each MOSFET. This provides a realistic simulation of actual CMOS devices because the substrate terminals cannot always be shorted to the source terminals in integrated circuits. If there is time, you may demonstrate your simulation at the end of the main meeting outlined in the previous section; otherwise, you may schedule a separate Zoom session with me.
- Option 2: Construct and demonstrate a physical version of the logic gate assigned to your group using the CD4007 chip available via the ECE Department's component database. A datasheet for the CD4007 is available on the Laboratory page at the course web site. Design your layout so that the logic gate's output voltage v_O and the node voltage between the two "stacked" MOSFETs (Q_3 and Q_4 in gate A and Q_1 and Q_2 in gate B) can be easily measured using the benchtop multimeter. Devise an efficient way to switch each input terminal between logical 0 (0 V) and logical 1 (V_{DD}) to allow rapid, real-time changes. Clearly label or otherwise indicate input A and input B. If there is time, you may demonstrate your circuit at the end of the main meeting outlined in the previous section; otherwise, you may schedule a separate meeting with me.

Lab Scoring Criteria

Each group member will receive a score based on the following criteria quantized at the indicated levels. The first two criteria will constitute a group base score; that is, each group member will receive the same scores. The score for the third criterion will be assessed independently for each group member and will be determined by that person's explanation during the post-lab meeting. The rubrics posted on the Laboratory page at the course web site will guide the assignment of the various scores.

0, 20, 40, 50, 55, 60 pts	Properly completed truth and region-of-operation table (group)
0, 2, 5, 8, 10 pts	Quality and effectiveness of supporting visual aids (group)
0, 8, 15, 23, 30 pts	Quality of response to prompt (indiv.)

According to university policy, meetings may not take place after classes end for the semester. Thus, partial credit for a late meeting will not be available. However, if the meeting is not completed, each member of the group can nevertheless receive up to 70 pts (same score for each member) if the worksheet containing the truth and region-of-operation table is submitted by 11:59 pm on Tuesday, December 5.

Group Assignments

The randomly generated groups for this lab exercise are listed below. The letter next to your names indicates the logic gate circuit assigned to your group.

Samuels-Powick-Flynn (A)
 Ren-Jeong-Freedenberg (B)
 Ashnault-Regec-Beebe (A)
 Miller-Andrews-Baganski (B)
 Bailey-Beaudette-Tuncel (A)
 Youn-Jiorle-Zhang (B)
 Hackett-Sago-Piper (A)

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